

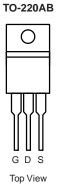
APM1102PF-VB Datasheet P-Channel 100 V (D-S) 175 °C MOSFET

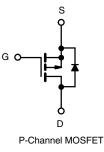
PRODUCT SUMMARY				
V _{DS} (V)	- 100			
$R_{DS(on)}(\Omega)$ at V_{GS} = - 10 V	0.033			
$R_{DS(on)}(\Omega)$ at V_{GS} = - 4.5 V	0.037			
I _D (A)	- 50			
Configuration	Single			

FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- Package with Low Thermal Resistance
- + 100 % $\rm R_g$ and UIS Tested
- Compliant to RoHS Directive 2002/95/EC







ABSOLUTE MAXIMUM RATINGS	(T _C = 25 °C, unles	s otherwise noted	(k	
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	- 100	V
Gate-Source Voltage		V _{GS}	± 20	v
Continuous Drain Current	$T_C = 25 \ ^\circ C$	۱ _D	- 50	
Continuous Drain Current	T _C = 125 °C	١D	- 30	
Continuous Source Current (Diode Conduction) ^a		I _S	- 50	А
Pulsed Drain Current ^b		I _{DM}	- 180	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	- 44	
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	96	mJ
Mariana Damar Diasia atia ab	$T_{\rm C} = 25 ^{\circ}{\rm C} \qquad \qquad 136$	136	W	
Maximum Power Dissipation ^b	T _C = 125 °C	гЪ	45	٧V
Operating Junction and Storage Temperature F	lange	T _J , T _{stg}	- 55 to + 175	°C

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	50	°C/W
Junction-to-Case (Drain)		R _{thJC}	1.1	C/W

Notes

a. Package limited.

b. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

SPECIFICATIONS ($T_C = 25 \text{ °C}$, unless otherwise noted)								
PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static	•				•		•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$		- 100	-	-	v	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{GS} , I _D = - 250 μA	- 1.0	-	-2.5	v	
Gate-Source Leakage	I _{GSS}	V _{DS} =	0 V, V_{GS} = ± 20 V	-	-	± 100	nA	
		$V_{GS} = 0 V$	V _{DS} = - 100 V	-	-	- 1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V_{DS} = - 100 V, T_{J} = 125 °C	-	-	- 50		
		$V_{GS} = 0 V$	V_{DS} = - 100 V, T_{J} = 175 °C	-	-	- 250		
On-State Drain Current ^a	I _{D(on)}	V_{GS} = - 10 V	$V_{DS} \le$ - 5 V	- 30	-	-	А	
		$V_{GS} = -10 V$	I _D = - 9.2 A	-	0.033	-	Ω	
Drain-Source On-State Resistance ^a	Brack	$V_{GS} = -10 V$	I_D = - 9.2 A, T_J = 125 °C	I	0.074	-		
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = -10 V$	I_D = - 9.2 A, T_J = 175 °C	I	0.093	-		
		$V_{GS} = -4.5 V$	I _D = - 7.7 A	I	0.037	-		
Forward Transconductance ^b	9 _{fs}	V _{DS} = - 15 V, I _D = - 9.2 A		-	35	-	S	
Dynamic ^b								
Input Capacitance	C _{iss}			I	4433	5545		
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	$V_{GS} = 0 V$ $V_{DS} = -25 V$, f = 1 MHz	-	301	380	pF	
Reverse Transfer Capacitance	C _{rss}			-	208	260		
Total Gate Charge ^c	Qg		V _{DS} = - 50V, I _D = - 9.2 A	-	96	144		
Gate-Source Charge ^c	Q _{gs}	$V_{GS} = - 10 V$		-	8.4	-	nC	
Gate-Drain Charge ^c	Q _{gd}			-	23.5	-		
Gate Resistance	Rg		f = 1 MHz		3.13	4.7	Ω	
Turn-On Delay Time ^c	t _{d(on)}			-	11	17		
Rise Time ^c	t _r	$V_{DD} = -50 \text{ V}, \text{ R}_{\text{I}} = 6.49 \Omega$		-	11	17		
Turn-Off Delay Time ^c	t _{d(off)}	I _D ≅ - 7.7 A, '	$V_{\rm GEN} = -10 \rm V, R_g = 1.0 \Omega$	-	78	117	ns	
Fall Time ^c	t _f	7		-	15	23	1	
Source-Drain Diode Ratings and Chara	acteristics ^b	•						
Pulsed Current ^a	I _{SM}			-	-	- 150	Α	
Forward Voltage	V _{SD}	I _F =	- 7.7 A, V _{GS} = 0 V	-	- 0.8	- 1.5	V	

Notes

a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

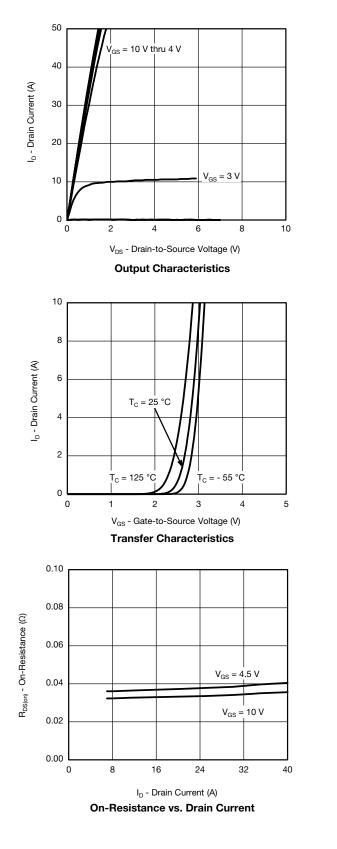
c. Independent of operating temperature.

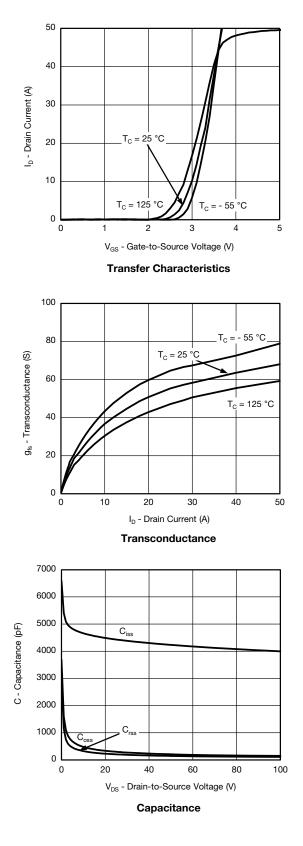
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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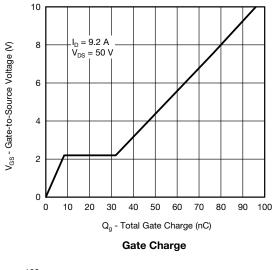
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)

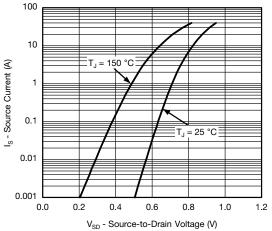




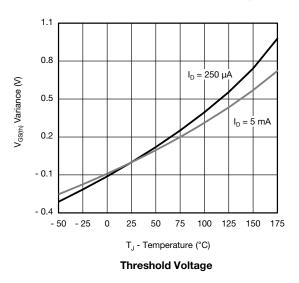


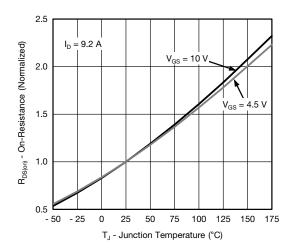
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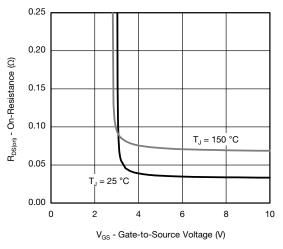


Source Drain Diode Forward Voltage

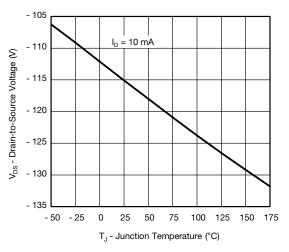




On-Resistance vs. Junction Temperature



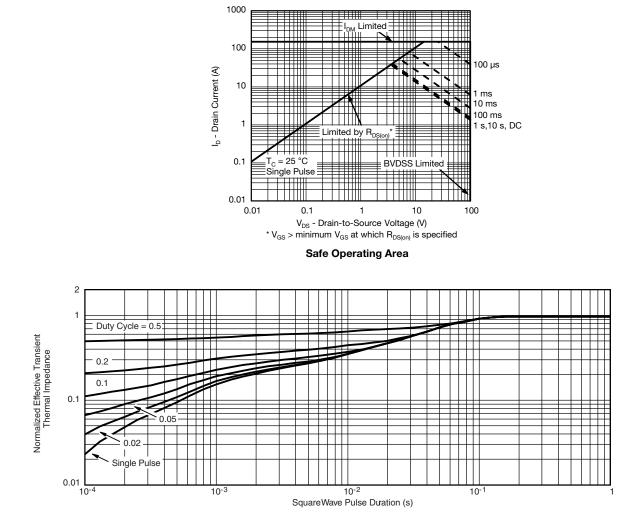
On-Resistance vs. Gate-to-Source Voltage



Drain Source Breakdown vs. Junction Temperature



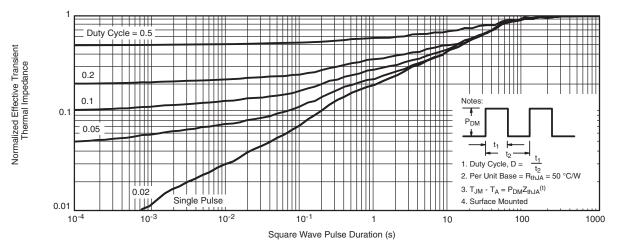
THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient

Note

• The characteristics shown in the two graphs

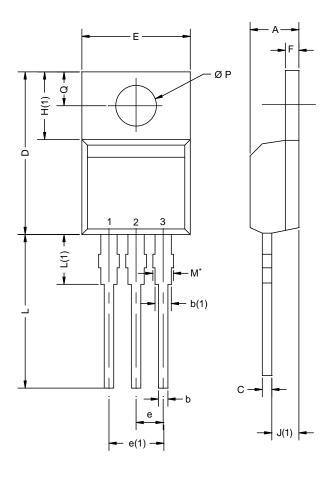
- Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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